

IN THE CLAIMS:

Claim 1 (previously amended): A heat emitting probe comprising:  
a conductive carbon nanotube probe needle with a base end portion thereof  
fastened to a holder and a tip end portion thereof protruding,  
a heat emitting body provided on a circumferential surface of said conductive  
carbon nanotube probe needle, and  
a conductive carbon nanotube lead wire fastened to said heat emitting body.

Claim 2 (previously amended): A heat emitting probe comprising:  
a conductive carbon nanotube probe needle with a base end portion thereof  
fastened to a holder and a tip end portion thereof protruding,  
a heat emitting body provided on a circumferential surface of said conductive  
carbon nanotube probe needle,

a conductive carbon nanotube lead wire fastened to said heat emitting body, and  
a means for causing an electric current to pass through both ends of said  
conducting carbon nanotube lead wire and said conductive carbon nanotube probe needle,  
wherein

an electric current is caused to pass through said heat emitting body.

Claim 3 (previously amended): The heat emitting probe according to Claim 2, wherein:  
an atomic force microscope (AFM) cantilever in which a protruding portion used  
as said holder is formed on a cantilever portion thereof is employed,  
two electrode films are provided on said cantilever portion,  
one end of said conductive carbon nanotube lead wire is connected to one of said  
electrode films, and  
said conductive carbon nanotube probe needle is connected to another of said  
electrode films, wherein  
said electric current is caused to pass between said electrode films.

Claim 4 (previously amended): The heat emitting probe according to Claim 2, wherein:  
an atomic force microscope (AFM) cantilever in which a protruding portion used  
as said holder is formed on a cantilever portion thereof is employed,  
two electrode films are provided on said cantilever portion,

one end of said conductive carbon nanotube lead wire is connected to one of said electrode films, and

said conductive carbon nanotube probe needle and another of said electrode films are connected by means of another conductive nanotube lead wire, wherein

said electric current is caused to pass between said electrode films.

Claim 5 (previously amended): A heat emitting probe apparatus comprising:

said heat emitting probe according to Claim 2, 3 or 4,

a scanning mechanism that allows a tip end of said conductive carbon nanotube probe needle of said heat emitting probe to scan over a sample, and

a control circuit which passes an electric current through said tip end of said conductive carbon nanotube probe needle, wherein

said tip end of said conductive carbon nanotube probe needle scans a surface of a sample.

Claim 6 (previously amended): The heat emitting probe apparatus according to Claim 5, wherein

said sample is a thermal recording medium, and

said tip end of said conductive carbon nanotube probe needle is heated by said heat emitting probe, and wherein

information is recorded by means of a hole pattern formed in a surface of said thermal recording medium.

Claim 7 (cancelled).

Claim 8 (cancelled).